

**Search Notes**

Application/Control No.

10/772,324

Examiner

Winnie Yip

Applicant(s)/Patent under  
Reexamination

LU, WEN-CHIEH

Art Unit

3637

**SEARCHED**

Class	Subclass	Date	Examiner
135	15.1 16 910	9/23/2005	WSY
362	102 103	9/23/2005	WSY
✓	234 800	✓	✓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Searched in EAST	9/23/2005	WSY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner